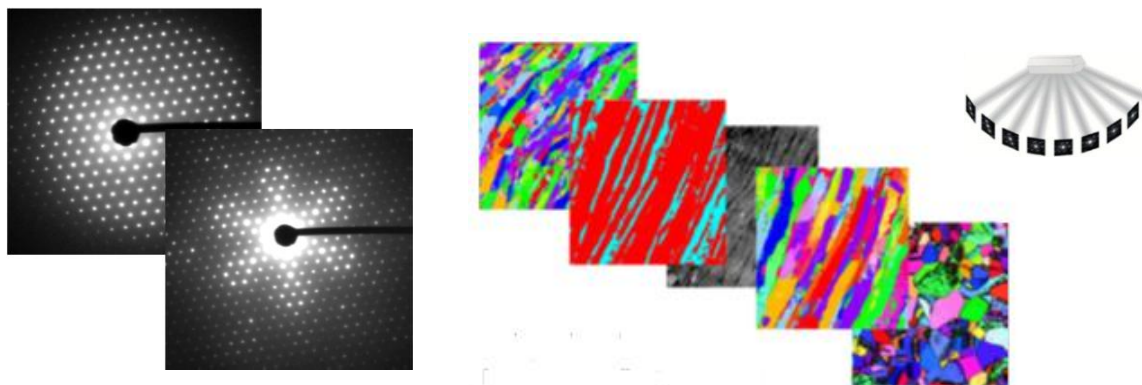


JULY 8th 2013

**NEW TEM CHARACTERIZATION TECHNIQUES FOR NANO-MATERIALS:
FROM ORIENTATION AND PHASE MAPPING (EBSD-TEM like)
TO STRAIN ANALYSIS & 3D PRECESSION ELECTRON DIFFRACTION
TOMOGRAPHY**

IISc, TechnoS Instruments & NanoMEGAS cordially welcomes you to a dedicated mini-workshop for the novel TEM characterization techniques: Precession Electron Diffraction and Orientation and Phase Mapping. There will be theoretical and application sessions followed by practical hands-on sessions.



**Advanced Facility for Microscopy and Microanalysis
Indian Institute of Science
Gulmohar Marg, Near Centre for Neuroscience, Mathikere,
Bangalore, Karnataka 560012
Contact No: +91-080-2293 2034/35**

Monday, July 8 2013

09:00 – 09:15 : Welcome Notes by Prof. Dipankar Baneerjee, IISc
**09:15 – 10:45 : ASTAR : Applications of Orientation /Phase Imaging in TEM by
Prof. Muriel Veron (Grenoble, INP University)**
10:45 – 11:00 : Tea/Coffee Break
**11:00 – 12:30 : Combine Strain Mapping with Orientation Mapping at nm scale for any
material in TEM : the TopSPIN framework(Video Presentation)
by Mr. Vrettos Stelliou, NanoMEGAS**
12:30 – 13:30 : Lunch
13:30 – 14:00 : Presentation by Prof. Dipankar Baneerjee 's Group on "ASTAR"
14:00 – 14:15 : Tea/Coffee Break
14:15 – 16:45 : Live Demo on ASTAR With Prof. Muriel Veron
16:45 – 17:00 : Conclusion/ Thanks Giving by Prof. Muriel Veron

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